Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attomey's Docket No. 12732-207001	Application No. 10/756,756	
1	closure Statement oplicant	Applicant Hajime Kimura et al.		
(Use several st	neets if necessary)	Filing Date January 14, 2004	Group Art Unit 2673 2629	

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	closure Statement	Applicant Hajime Kimura et al.		
(Use several sheets if necessary)		Filing Date	Group Art Unit	
(37 CFR 61.98(b))		January 14, 2004	2673 2629	

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Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hajime Kimura et al.		
		Filing Date January 14, 2004	Group Art Unit 2673 2629	

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1	closure Statement	Applicant Hajime Kimura et al.		
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(37 CFR \$1.98(b))

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Patent and Trademark Office

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Applicant
Hajimo Kimura et al.
Filing Date
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	closure Statement	Applicant Hajime Kimura et al.		
(Use several st	néets if necessary)	Filing Date January 14, 2004	Group Art Unit 2629	

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